

DESCRIPTION

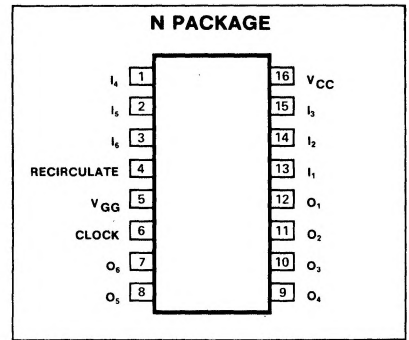
The 2518 32-bit and the 2519 40-bit recirculating static shift registers consist of enhancement mode p-channel silicon gate MOS devices intergrated on a single monolithic chip. Internal recirculation logic plus TTL/DTL level clock signals are provided for maximum interfacing ease.

TRUTH TABLE

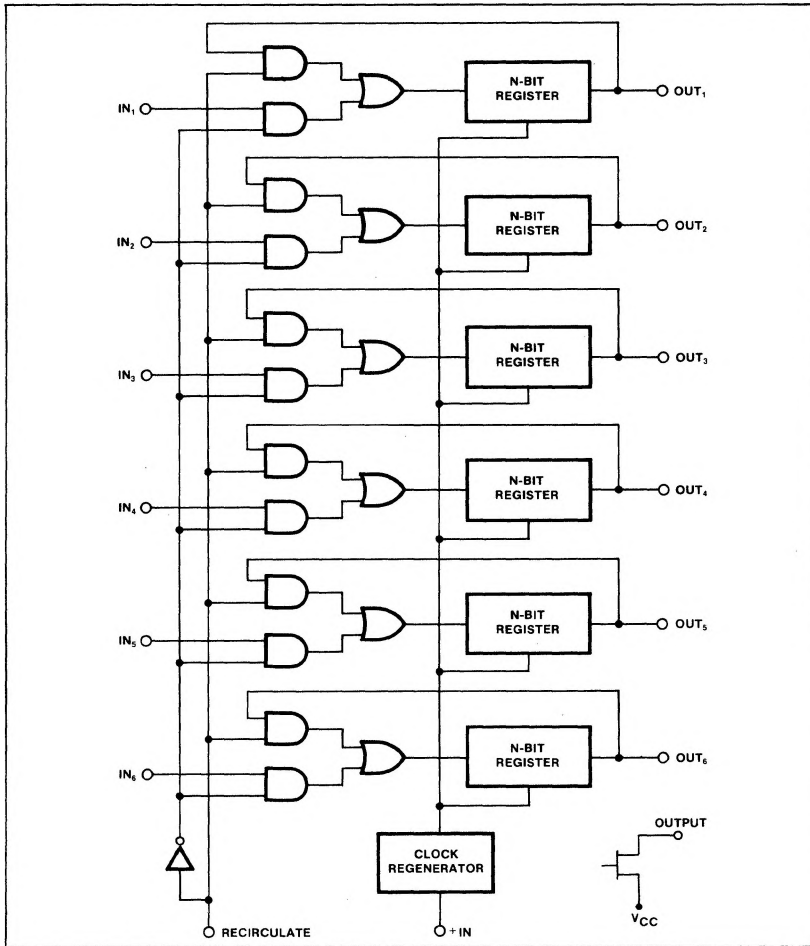
RECIRCULATE	INPUT	FUNCTION
1	0	Recirculate
1	1	Recirculate
0	0	"0" is written
0	1	"1" is written

Data is read out when output enable is low. Output is tristated when output enable is high.

PIN CONFIGURATION



BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS¹

PARAMETER	RATING	UNIT
T_A Temperature range		$^{\circ}C$
Operating ²	0 to +70	
T_{STG} Storage	-65 to 150	
P_D Power dissipation at $T_A = 70^{\circ}C$	640	mW
Data and clock input voltages and supply voltages with respect to V_{CC}	0.3 to -20	V

DC ELECTRICAL CHARACTERISTICS $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$, $V_{CC} = +5\text{V} \pm 5\%$, $V_{GG} = -12\text{V} \pm 5\%$
 unless otherwise specified.^{3,4,5,6,7}

PARAMETER	TEST CONDITIONS	LIMITS			UNIT
		Min	Typ	Max	
V_{IL} V_{IH} V_{ILC} V_{IHC}	Input voltage ⁸ Low High Clock low Clock high				V
		3.4		0.6 5.3 0.6 5.3	
V_{OL} V_{OH}	Output voltage Low High				V
			0.5		
I_{LO} I_{LC}	Leakage current Output Clock				nA
			10 10	1000 500	
I_{LI} I_{GG}	Input load current Supply current				nA mA
			10 16	500 25	
C_{IN} C_ϕ	Capacitance Input Clock				pF
			5 6	7 7	

AC ELECTRICAL CHARACTERISTICS $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$, $V_{CC} = +5\text{V} \pm 5\%$, $V_{GG} = -12\text{V} \pm 5\%$, $V_{ILC} = 0.4\text{V}$ to 4.0V

PARAMETER	TO	FROM	LIMITS			UNIT
			Min	Typ	Max	
Freq.	Clock rep rate		dc	3	2	MHz
$t_{\phi PW}$ $t_{\phi PW}$	Pulse width Clock ¹⁰ Clock		.300 .200		100 dc	μs
t_{DS} t_{DH}	Setup and hold time Setup time Hold time	Clock in Data in	100 70			ns
t_{RS} t_{RH}	Setup time Hold time	Clock Recirculate	150 50			
$t_{R,TF}$ t_A	Clock pulse transition Clock to data out delay	Data Clock		300	5 350	μs ns

NOTES

- Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a 150°C maximum junction temperature and a thermal resistance of $125^\circ\text{C}/\text{W}$, junction to ambient.
- All inputs are protected against static charge.
- Parameters are valid over operating temperature range unless specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at $+25^\circ\text{C}$ and typical supply voltages.
- Guaranteed input levels are stated for worst case conditions including a $\pm 5\%$ variation in V_{CC} and a temperature variation of 0°C to $+70^\circ\text{C}$. Actual input requirements with respect to V_{CC} are $V_{IH} = V_{CC} - 1.85\text{V}$ and $V_{IL} = V_{CC} - 4.15\text{V}$.
- V_{OL} is dependent on R_L and input characteristics of driven gate.
- Input rise and fall times = 10ns. Output load is 1 TTL gate.
- For static operation, clock must be stopped in TTL high state in order to retain data (see clock pulse width specification).

TIMING DIAGRAM

